

**Notice of References Cited**

Application/Control No.

10/519,084

Applicant(s)/Patent Under  
Reexamination  
WATANABE ET AL.

Examiner

Tsz K. Chiu

Art Unit

2822

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,157,359	01-2007	Park et al.	438/585
*	B	US-2002/0153579	10-2002	Yamamoto, Ichiro	257/412
	C	US-			
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	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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